

Notice of References Cited	Application/Control No. 10/749,542	Applicant(s)/Patent Under Reexamination SUH ET AL.	
	Examiner Raj K. Jain	Art Unit 2616	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2003/0007519	01-2003	Murton et al.	370/539
*	C	US-2003/0074449	04-2003	Smith et al.	709/226
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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